International Rectifier

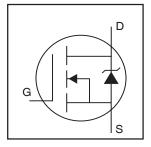
Features

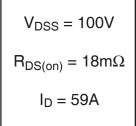
- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free

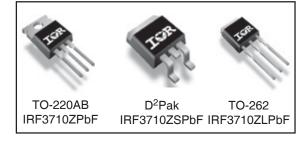
Description

This HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in a wide variety of applications.

IRF3710ZPbF IRF3710ZSPbF IRF3710ZLPbF HEXFET® Power MOSFET







Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	59	Α
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (See Fig. 9)	42	
I _{DM}	Pulsed Drain Current ①	240	
P _D @T _C = 25°C	Maximum Power Dissipation	160	W
	Linear Derating Factor	1.1	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	170	mJ
E _{AS} (tested)	Single Pulse Avalanche Energy Tested Value ⑦	200	
I _{AR}	Avalanche Current ①	See Fig.12a,12b,15,16	Α
E _{AR}	Repetitive Avalanche Energy ©		mJ
TJ	Operating Junction and	-55 to + 175	°C
T _{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		0.92	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50		
$R_{\theta JA}$	Junction-to-Ambient		62	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount, steady state)®		40	

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Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.10		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		14	18	mΩ	V _{GS} = 10V, I _D = 35A ⊕
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
gfs	Forward Transconductance	35			S	$V_{DS} = 50V, I_D = 35A$
I _{DSS}	Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 100V, V_{GS} = 0V$
				250	Ī	$V_{DS} = 100V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			200	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-200	İ	V _{GS} = -20V
Q_g	Total Gate Charge		82	120	nC	$I_D = 35A$
Q_{gs}	Gate-to-Source Charge		19	28		$V_{DS} = 80V$
Q_{gd}	Gate-to-Drain ("Miller") Charge		27	40		V _{GS} = 10V ④
t _{d(on)}	Turn-On Delay Time		17		ns	$V_{DD} = 50V$
t _r	Rise Time		77			$I_D = 35A$
t _{d(off)}	Turn-Off Delay Time		41			$R_G = 6.8\Omega$
t _f	Fall Time		56		1	V _{GS} = 10V ④
L _D	Internal Drain Inductance		4.5		nΗ	Between lead,
						6mm (0.25in.)
L _S	Internal Source Inductance		7.5			from package
						and center of die contact
C _{iss}	Input Capacitance		2900		pF	$V_{GS} = 0V$
C _{oss}	Output Capacitance		290			$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance		150			f = 1.0MHz, See Fig. 5
C _{oss}	Output Capacitance		1130			$V_{GS} = 0V$, $V_{DS} = 1.0V$, $f = 1.0MHz$
C _{oss}	Output Capacitance		170			$V_{GS} = 0V, V_{DS} = 80V, f = 1.0MHz$
C _{oss} eff.	Effective Output Capacitance		280			$V_{GS} = 0V$, $V_{DS} = 0V$ to $80V$

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			59		MOSFET symbol
	(Body Diode)				Α	showing the
I _{SM}	Pulsed Source Current		_	240		integral reverse
	(Body Diode) ①					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 35A$, $V_{GS} = 0V$ ④
t _{rr}	Reverse Recovery Time		50	75		$T_J = 25^{\circ}C$, $I_F = 35A$, $V_{DD} = 25V$
Q_{rr}	Reverse Recovery Charge		100	160	nC	di/dt = 100A/µs ④
t _{on}	Forward Turn-On Time	Intrinsi	turn-or	time is	negligib	le (turn-on is dominated by LS+LD)

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- R_G = 25 $\!\Omega_{\rm ,}$ I_{AS} = 35 A, V_{GS} =10 V. Part not recommended for use above this value.
- $\ensuremath{ \begin{tabular}{l} \ensuremath{ \begin{tabular$ $T_J \le 175$ °C.
- ④ Pulse width \leq 1.0ms; duty cycle \leq 2%.
- © Coss eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- avalanche performance.
 - ① This value determined from sample failure population. 100% tested to this value in production.
 - ® This is applied to D2Pak, when mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.

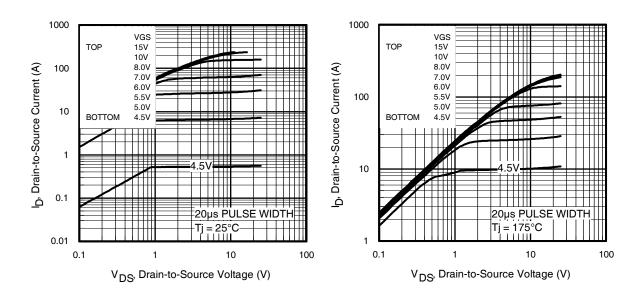


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics

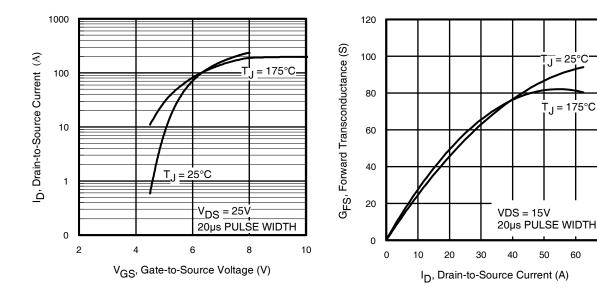
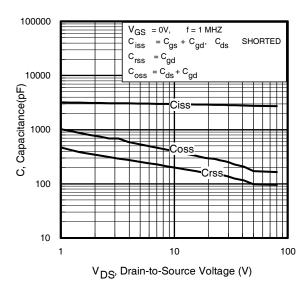


Fig 3. Typical Transfer Characteristics

Fig 4. Typical Forward Transconductance vs. Drain Current

70



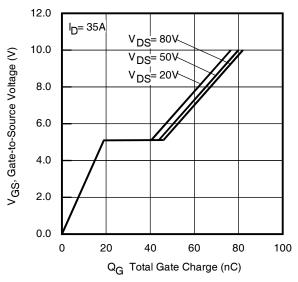
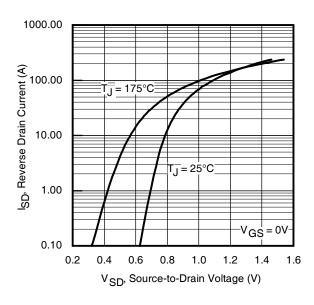


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



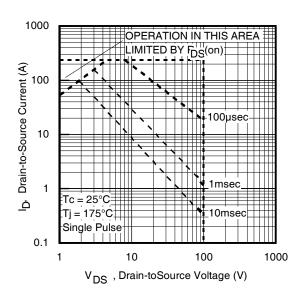


Fig 7. Typical Source-Drain Diode Forward Voltage

Fig 8. Maximum Safe Operating Area

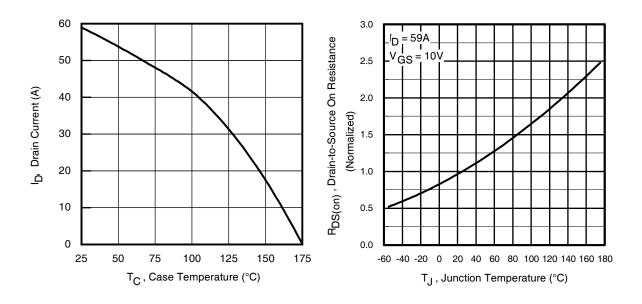


Fig 9. Maximum Drain Current vs. Case Temperature

Fig 10. Normalized On-Resistance vs. Temperature

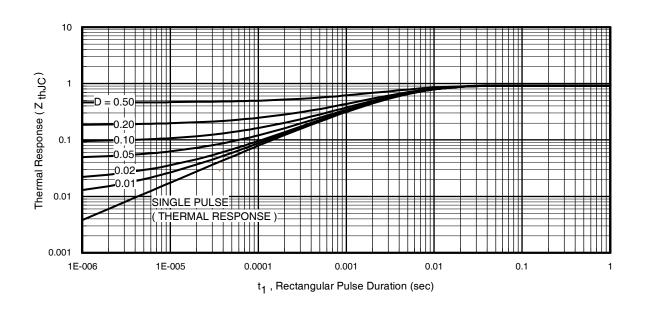


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

IRF3710Z/S/LPbF

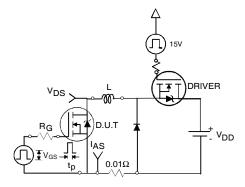


Fig 12a. Unclamped Inductive Test Circuit

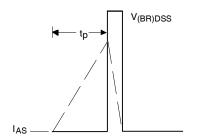


Fig 12b. Unclamped Inductive Waveforms

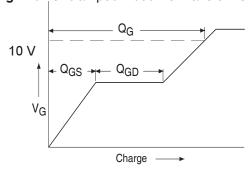


Fig 13a. Basic Gate Charge Waveform

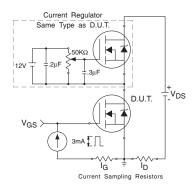


Fig 13b. Gate Charge Test Circuit 6

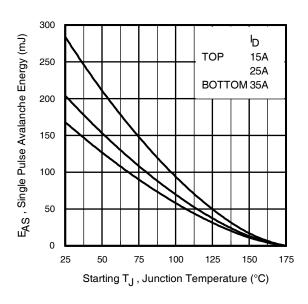


Fig 12c. Maximum Avalanche Energy vs. Drain Current

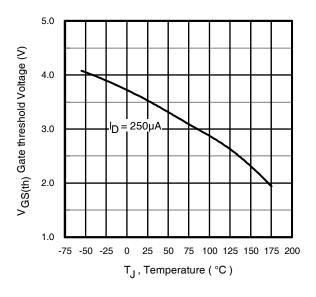


Fig 14. Threshold Voltage vs. Temperature www.irf.com

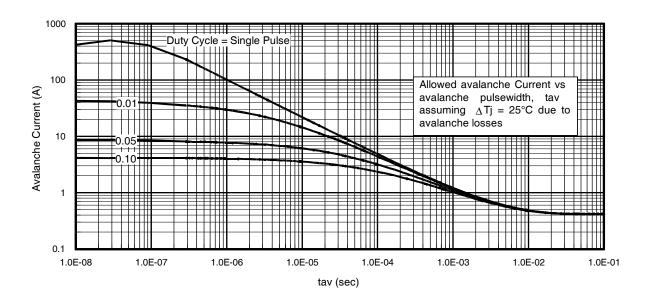


Fig 15. Typical Avalanche Current vs. Pulsewidth

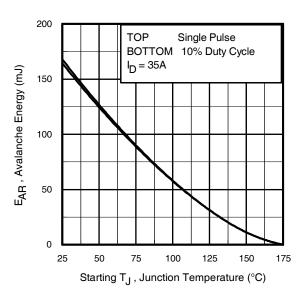


Fig 16. Maximum Avalanche Energy vs. Temperature www.irf.com

Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

- Avalanche failures assumption:
 Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long asT_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- P_D (ave) = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16). t_{av} = Average time in avalanche.
 - D = Duty cycle in avalanche = $t_{av} \cdot f$

 $Z_{th,JC}(D, t_{av})$ = Transient thermal resistance, see figure 11)

$$\begin{split} P_{D\;(ave)} &= 1/2\;(\;1.3 \cdot BV \cdot I_{av}) = \Delta T/\;Z_{thJC} \\ I_{av} &= 2\Delta T/\;[1.3 \cdot BV \cdot Z_{th}] \\ E_{AS\;(AR)} &= P_{D\;(ave)} \cdot t_{av} \end{split}$$

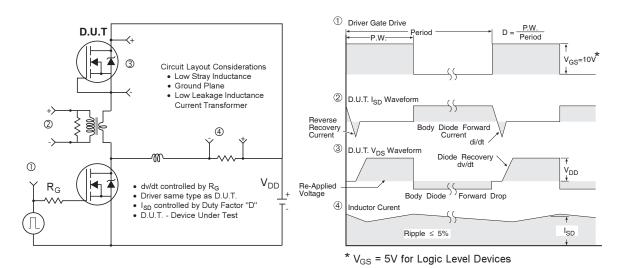


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

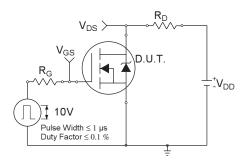


Fig 18a. Switching Time Test Circuit

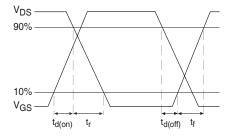
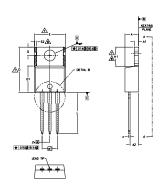


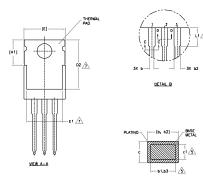
Fig 18b. Switching Time Waveforms

IRF3710Z/S/LPbF

TO-220AB Package Outline

Dimensions are shown in millimeters (inches)





- S

 DIRENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.
 DIRENSIONS ARE SHOWN IN INCHES [MILLWEITERS].

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 AND SMOULATION PREFOLIABRIES AND EALDER AC (MAND).

 OUTLINE CONFERNS TO JUDICE OF 2-202, EXCEPT AZ (MAND) DD Z

 OUTLINE CONFERNS TO JUDICE OF 2-202, EXCEPT AZ (MAND).

- OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	MILLIM	ETERS	INC	HES	
	MIN.	MAX.	MIN.	MAX.	NOTES
A	3.56	4.83	.140	.190	
A1	0.51	1,40	.020	.055	
A2	2,03	2,92	.080	,115	
b	0.38	1,01	.015	.040	
ь1	0.38	0.97	.015	.038	5
b2	1,14	1,78	.045	.070	
b3	1.14	1.73	.045	.068	5
С	0.36	0,61	.014	.024	
c1	0.36	0.56	.014	.022	5
D	14,22	16,51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	11,68	12,88	.460	.507	7
Ε	9,65	10,67	.380	.420	4,7
E1	6.86	8.89	.270	.350	7
E2	-	0.76	-	.030	8
e		BSC	.100		
e1	5.08	5,08 BSC		BSC	
H1	5.84	6.86	.230	.270	7,8
L	12,70	14,73	.500	.580	
L1	3.56	4.06	.140	.160	3
øP	3.54	4.08	.139	.161	
Q	2,54	3,42	.100	.135	

LEAD ASSIGNMENTS ICRTs. CoPACK 1,- GATE 2,- COLLECTOR 3,- EMITTER 1.- ANODE 2.- CATHODE 3.- ANODE

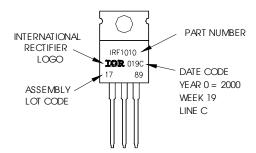
TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010

LOT CODE 1789

ASSEMBLED ON WW 19, 2000 IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead-Free"

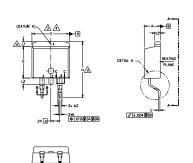


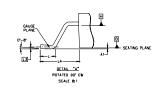
TO-220AB package is not recommended for Surface Mount Application

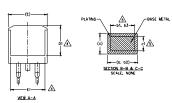
- 1. For an Automotive Qualified version of this part please see http://www.irf.com/product-info/datasheets/data/auirf3710z.pdf
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

D²Pak (TO-263AB) Package Outline

Dimensions are shown in millimeters (inches)



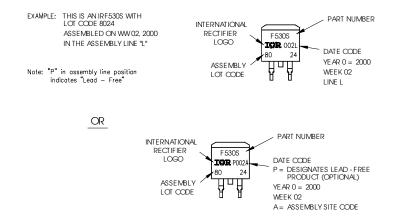




S Y M	DIMENSIONS				
В	MILLIM	ETERS	INC	O T E S	
0 L	MIN.	MAX.	MIN.	MAX.	S
Α	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
b	0.51	0.99	.020	.039	
b1	0.51	0.89	.020	.035	5
b2	1,14	1.78	.045	.070	
ь3	1,14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
c1	0.38	0,58	.015	.023	5
c2	1,14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270		4
E	9.65	10.67	.380	.420	3,4
E1	6.22	-	.245		4
е	2.54	BSC	.100	BSC	
Н	14,61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	-	1.65	-	.066	4
L2	-	1.78	-	.070	
L3	0.25	BSC	.010		
L4	4.78	5.28	.188	.208	

- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- DIMENSION D & E DO NOT INCLUDE WOLD FLASH. WOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTWOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- A THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY. 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

D²Pak (TO-263AB) Part Marking Information

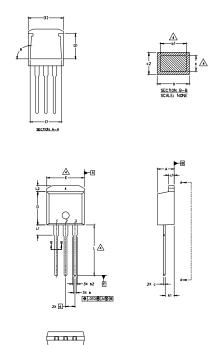


- 1. For an Automotive Qualified version of this part please see http://www.irf.com/product-info/datasheets/data/auirf3710z.pdf
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

IRF3710Z/S/LPbF

TO-262 Package Outline

Dimensions are shown in millimeters (inches)



S Y M		Ŋ			
B	MILLIM	ETERS	TERS INCHES		
B O L	MIN.	MAX.	MIN.	MAX.	N O T E S
Α	4.06	4.83	.160	.190	
A1	2.03	2.92	.080	.115	
ь	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	4
b2	1,14	1,40	.045	.055	
С	0.38	0.63	.015	.025	4
c1	1,14	1,40	.045	.055	
c2	0.43	.063	.017	.029	
D	8,51	9.65	.335	.380	3
D1	5.33		.210		
E	9.65	10.67	.380	.420	3
E1	6,22		.245		
e	2.54	BSC	.100		
L	13,46	14.09	.530	.555	
L1	3.56	3,71	.140	.146	
L2		1.65		.065	

LEAD ASSIGNMENTS

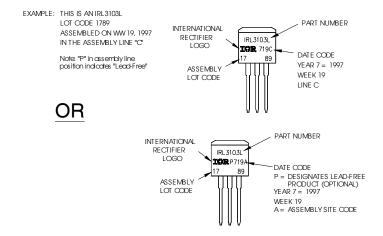
HEXFET

1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN 1 - GATE 2 - COLLECTOR

IGBT

3 - EMITTER

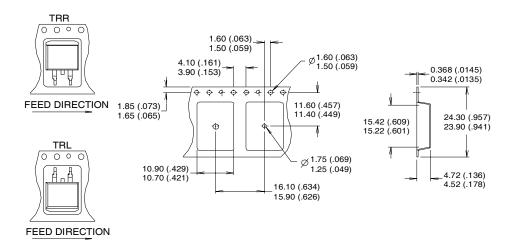
TO-262 Part Marking Information

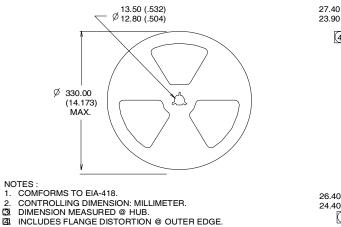


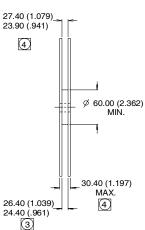
- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/ www.irf.com

D²Pak Tape & Reel Infomation

Dimensions are shown in millimeters (inches)







TO-220AB package is not recommended for Surface Mount Application.

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market.

Qualification Standards can be found on IR's Web site.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105

TAC Fax: (310) 252-7903

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